Electronic supplementary information (*ESI*)

Marked Improvement in the Stability of a Small Molecular Organic Photovoltaic by Interfacial Modification Using Self-assembled Monolayers to Prevent Indium Diffusion into the Active Layer

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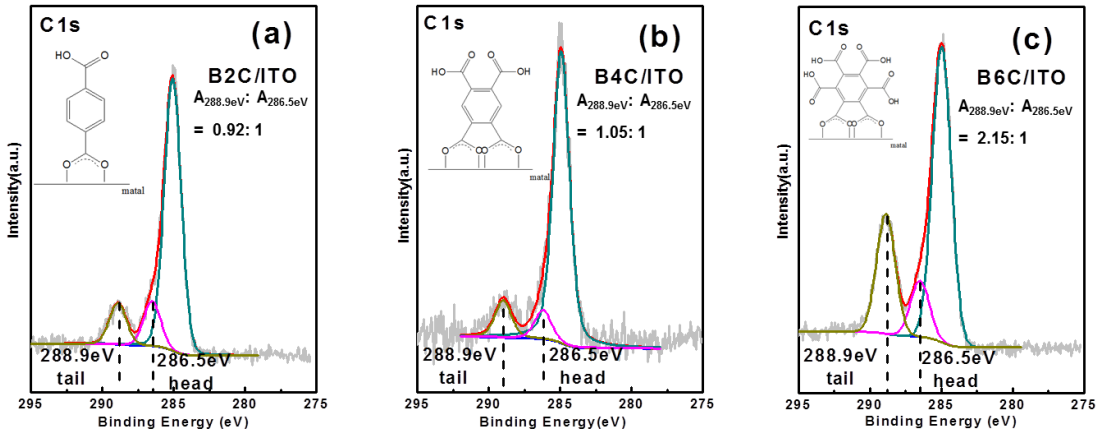

Fig. S1.

XPS spectra of (a) B2C-SAMs, (b) B4C-SAMs, and (c) B6C-SAMs on the ITO surface for C 1*s* core levels.

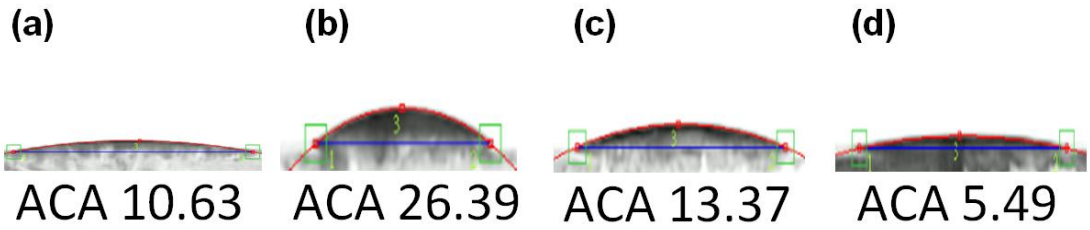

Fig. S2.

Contact angle (CA) images of (a) bare ITO, and various BxC-SAMs of the (b) B2C, (c) B4C, and (d) B6C group on the ITO substrate.

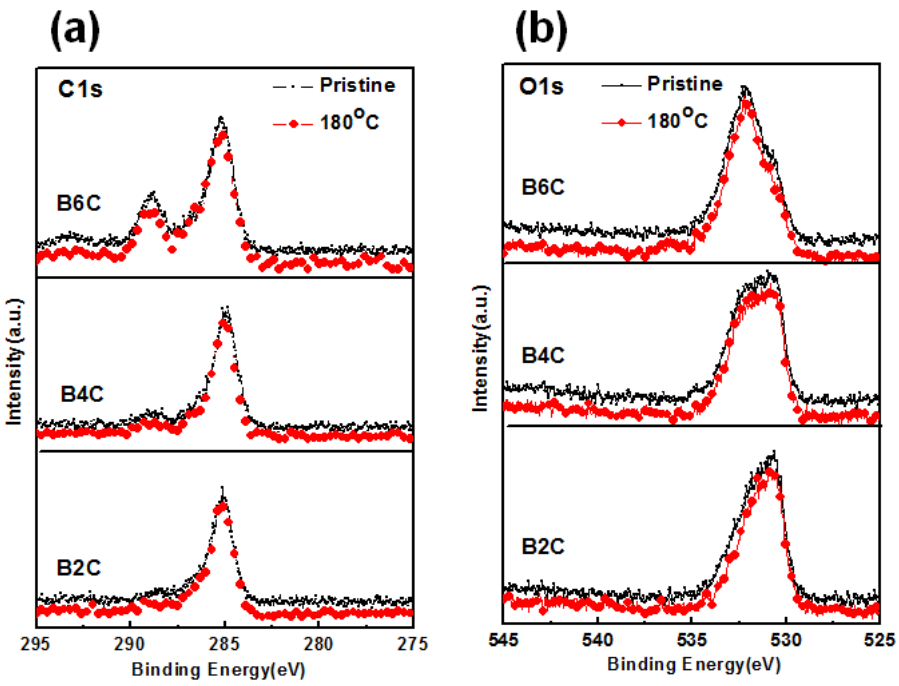

Fig. S3.

XPS spectra of (a) C 1*s* and (b) O 1*s* core levels for various BxC-SAMs on pristine and annealed (180°C, 3 min) ITO surfaces.

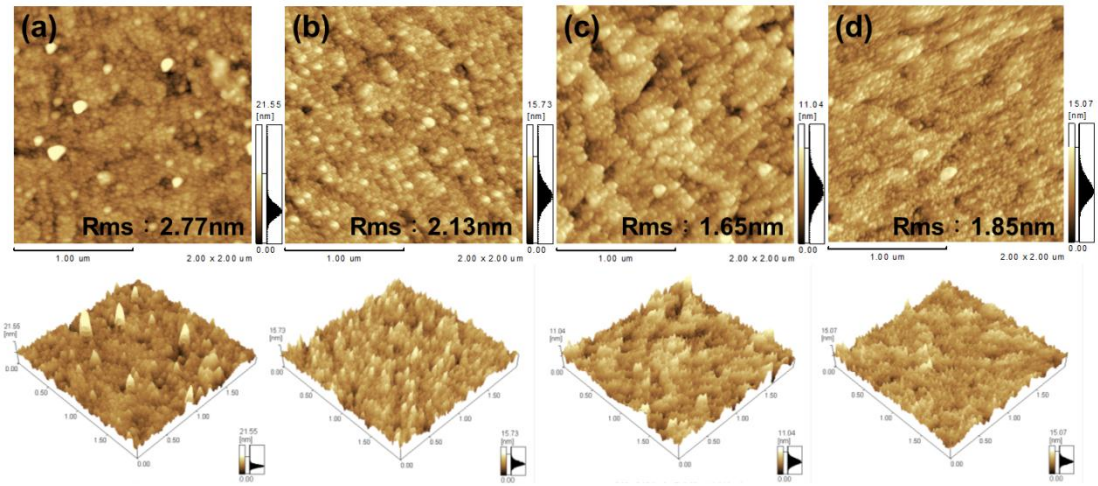

Fig. S4.

AFM images and surface roughness of (a) bare ITO, and (b) B2C, (c) B4C, and (d) B6C - modified substrate.

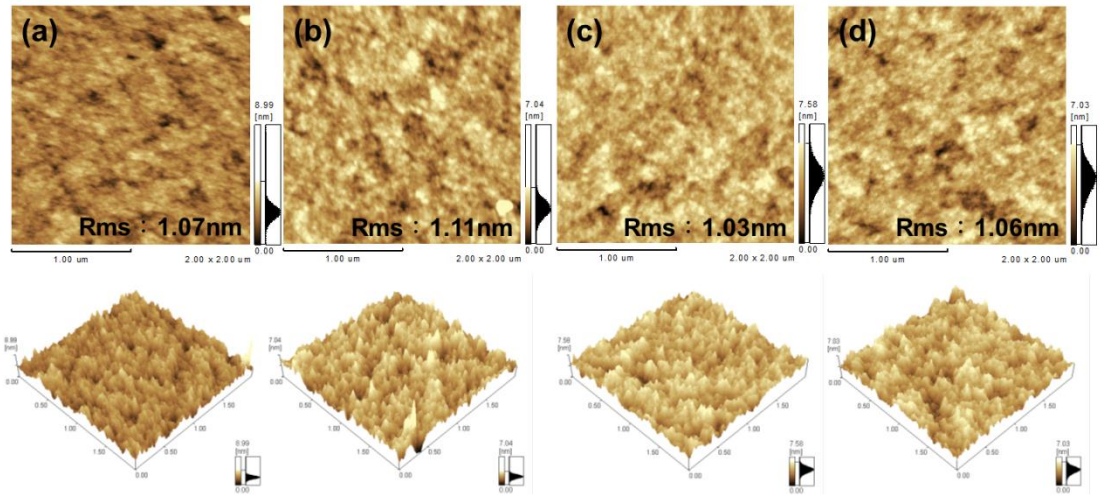

Fig. S5.

AFM images of 30 nm thick PEDOT:PSS films deposited on (a) bare ITO, and (b) B2C, (c) B4C, and (d) B6C - modified substrate.

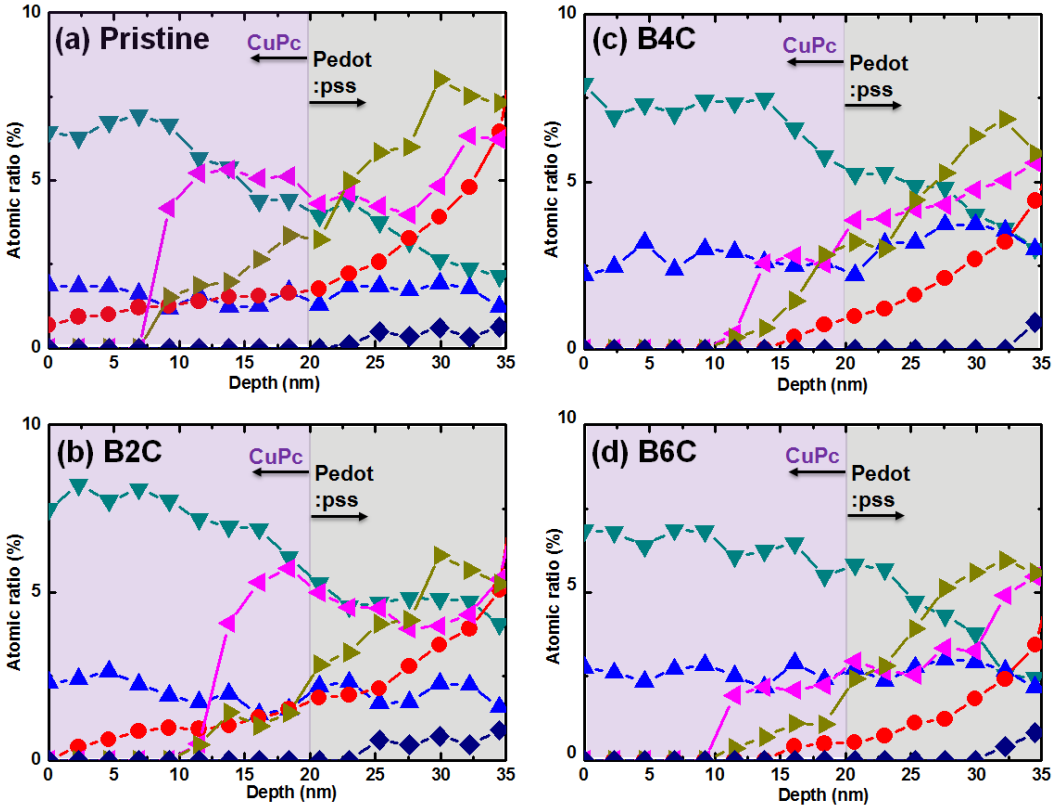

Fig. S6.

XPS depth profiles of (a) CuPc/PEDOT:PSS/ITO, (b) CuPc/PEDOT:PSS/B2C/ITO, (c) CuPc/PEDOT:PSS/B4C/ITO, and (d) CuPc/PEDOT:PSS/B6C/ITO, 91 days after fabrication.